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SN54S134, SN74S134 12-INPUT POSITIVE-NAND GATES WITH 3-STATE OUTPUTS

SDLS203

DECEMBER 1983 - REVISED MARCH 1988

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- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

description

The 'S134 feature three-state outputs that, when enabled, have the low impedance characteristics of a TTL output with additional drive capability at high logic levels to permit driving heavily loaded lines without external pull-up resistors. When disabled, both output transistors are turned off presenting a high-impedance state to the bus so the output will act neither as a significant load nor as a driver. The 'S134 outputs are diabled when G is high.



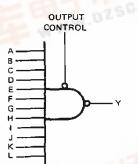
positive logic

·B·C D E

Output is off (disabled) when output control is high.

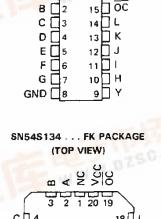
 $Y = \overline{A}$

dzsc.com



· G · H · I · J · K · L or

Y = Ā + B + Ĉ + D + Ē + F + G + H + ī + J + K + [



SN54S134 . . . J OR W PACKAGE

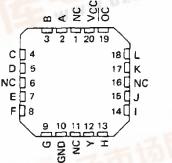
SN74S134 . . . D OR N PACKAGE

(TOP VIEW)

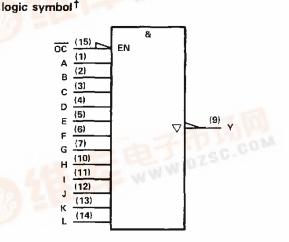
J16 UVCC

15 0C

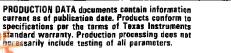
A []1





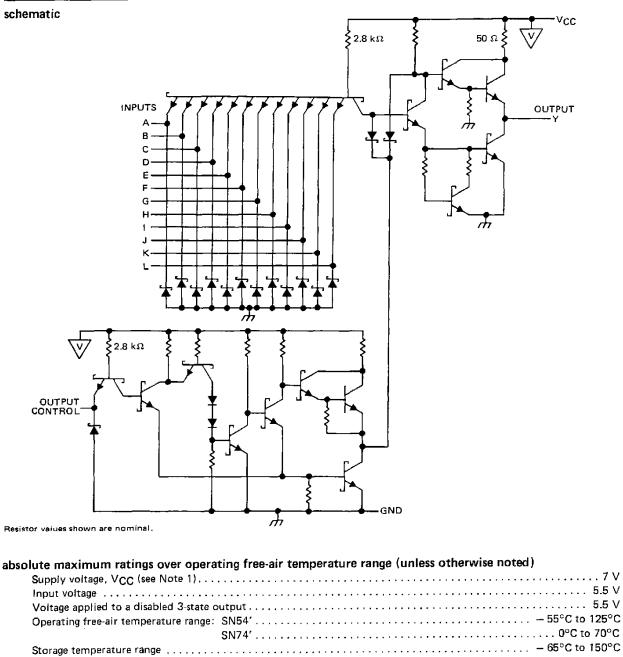


[†]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for D, J, N, and W packages.





SN54S134, SN74S134 12-INPUT POSITIVE NAND GATES WITH 3-STATE OUTPUTS



NOTE 1: Voltage values are with respect to network ground terminal.



SN54S134, SN74S134 **12-INPUT POSITIVE-NAND GATES WITH 3-STATE OUTPUTS**

recommended operating conditions

			SN54S134			SN74S134			
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
VCC Supply voltage	· · · · · · · · · · · · · · · · · · ·	4.5	5	5.5	4.75	5	5.25	V	
VIH High-level input vol	tage	2			2			V	
VIL Low-level input vol	tage			0.8			0.8	V	
IOH High-level output c	urrent			2			- 6.5	mΑ	
IOL Low-level output co	urrent			20			20	mΑ	
TA Operating free-air to	emperature	- 55		125	0		70	°C	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS [†]		SN54S134			5				
			MIN	TYP ‡	MAX	MIN	TYP‡	MAX	UNI.	
VIK	V _{CC} = MIN, I _I =18 mA					- 1.2			- 1.2	V
Vou	VCC = MIN,	V _{1H} = 2 V	¹ ОН = - 2 m А	2.4	3,4					v
	V _{IL} = 0.8 V		I _{OH} = → 6.5 mA				2.4	3.2		ľ.
	V _{CC} = MIN,	V _{IH} = 2 V,	V _{IL} = 0.8 V,			0.5			0.5	v
	I _{OL} = 20 mA					0.5			0.5	v
	V _{CC} = MAX,	V _{1H} = 2 V,	Vo = 2.4 V			50			50	
	V _{IL} ≖ 0.8 V		V _O = 0.5 V			- 50			- 50	μΑ
1	V _{CC} = MAX,	V1 = 5.5 V	•			1			1	mA
ΠН	VCC = MAX,	V1 = 2.7 V				50			50	Aپ
, IL	V _{CC} = MAX,	VI ≖ 0.5 V	<u>_</u>		-	- 2			- 2	mΑ
losš	V _{CC} = MAX			- 40		- 100	- 4 0		- 100	mA
			Outputs high		7	13		7	13	
	V _{CC} = MAX		Outputs low		9	16		9	16	mA
			Outputs disabled		14	25		14	25	}

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

1 All typical values are at $V_{CC} = 5 V$, $T_A = 25^{\circ}C$. 5 Not more than one output should be shorted at a time, and duration of the short circuit should not exceed one second.

PARAMETER	TEST CONDITIONS		SN54S134			SN74S134			UNIT
		TEST CONDITIONS	MIN	TYP	MAX	MIN	ТҮР	MAX	
1PLH	$R_{L} = 280 \Omega$,	C _L = 15 pF		4	6		4	6	ns
^t PLH	$R_{L} = 280 \Omega$	CL = 50 pF		5.5			5.5		ns
tPHL	RL = 280 Ω,	С ∟ ≠ 15 рF		5	7.5		5	7.5	ns
tPHL	$R_L = 280 \Omega$,	CL = 50 pF		7			7		ns
^t PZH	P 290 ()	Cլ= 50 pF		13	19.5		13	19.5	ПS
^t PZL	К[-20032.			14	21		14	21	ns
^t РНZ	$R_L = 280 \Omega$	5.5 8.5	5.5	8.5	ns.				
^t PLZ		CL ~ 5 PF		9	14		9	14	ns

switching characteristics, VCC = 5 V, TA = 25° C (see note 2)

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



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